Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/705,386	LIU ET AL.	
Examiner	Art Unit	
Thien F. Tran	2811	

	SEARCHED				
Class	Subclass	Date	Examiner		
257	690, 713, 734, 737, 738, 778	7/3/2006	т		
257	782-784	7/3/2006	ΤΤ		
		- · · · · · · · · · · · · · · · · · · ·			
		<del></del>			
		.==			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	L			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR